

May 1991 Revised December 1998

74ACTQ823 Quiet Series™ 9-Bit D-Type Flip-Flop with 3-STATE Outputs

General Description

The ACTQ823 is a 9-bit buffered register. It features Clock Enable and Clear which are ideal for parity bus interfacing in high performance microprogramming systems. The ACTQ823 utilizes Fairchild Quiet Series™ technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series™ features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

Features

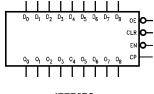
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Inputs and outputs on opposite sides of package allow easy interface with microprocessors
- Improved latch-up immunity
- Has TTL-compatible inputs

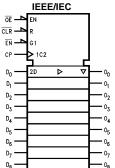
Ordering Code:

Order Number	Package Number	Package Description
74ACTQ823SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACTQ823SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300" Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering form.

Logic Symbols





Connection Diagram



Pin Descriptions

Pin Names	Description
D ₀ –D ₈	Data Inputs
D ₀ –D ₈ O ₀ –O ₈	Data Outputs
ŌĒ	Output Enable
CLR	Clear
CP	Clock Input
EN	Clock Enable

FACT™, Quiet Series™, FACT Quiet Series™ and GTO™ are trademarks of Fairchild Semiconductor Corporation.

Functional Description

The ACTQ823 consists of nine D-type edge-triggered flipflops. These have 3-STATE outputs for bus systems organized with inputs and outputs on opposite sides. The buffered clock (CP) and buffered Output Enable (\overline{OE}) are common to all flip-flops. The flip-flops will store the state of their individual D inputs that meet the setup and hold time requirements on the LOW-to-HIGH CP transition. With \overline{OE} LOW, the contents of the flip-flops are available at the outputs. When \overline{OE} is HIGH, the outputs go to the high impedance state. Operation of the \overline{OE} input does not affect the state of the flip-flops. In addition to the Clock and Output

Enable pins, there are Clear $\overline{(CLR)}$ and Clock Enable $\overline{(EN)}$ pins. These devices are ideal for parity bus interfacing in high performance systems.

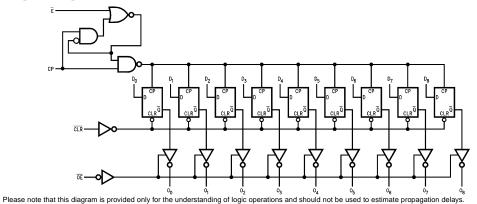
When \overline{CLR} is LOW and \overline{OE} is LOW, the outputs are LOW. When \overline{CLR} is HIGH, data can be entered into the flip-flops. When \overline{EN} is LOW, data on the inputs is transferred to the outputs on the LOW-to-HIGH clock transition. When the \overline{EN} is HIGH, the outputs do not change state, regardless of the data or clock input transitions.

Function Table

		Inputs			Internal	Output	Function
OE	CLR	EN	CP	D	Q	0	
Н	Χ	L	~	L	L	Z	High Z
Н	Χ	L	~	Н	Н	Z	High Z
Н	L	Χ	Χ	X	L	Z	Clear
L	L	Χ	Χ	X	L	L	Clear
Н	Н	Н	Χ	X	NC	Z	Hold
L	Н	Н	Χ	X	NC	NC	Hold
Н	Н	L	~	L	L	Z	Load
Н	Н	L	~	Н	Н	Z	Load
L	Н	L	~	L	L	L	Load
L	Н	L	~	Н	Н	Н	Load

- H = HIGH Voltage Level
- L = LOW Voltage Level
- - terial NC = No Change

Logic Diagram



140°C

Absolute Maximum Ratings(Note 1)

Supply Voltage (V_{CC}) -0.5V to +7.0V

DC Input Diode Current (I_{IK})

 $\begin{aligned} & \text{V}_{\text{I}} = -0.5 \text{V} & -20 \text{ mA} \\ & \text{V}_{\text{I}} = \text{V}_{\text{CC}} + 0.5 \text{V} & +20 \text{ mA} \end{aligned}$

DC Input Voltage (V_I) -0.5V to $V_{CC} + 0.5V$

DC Output Diode Current (I_{OK})

 $V_{O} = -0.5V$ -20 mA $V_{O} = V_{CC} + 0.5V$ +20 mA

DC Output Voltage (V_O) -0.5V to $V_{CC} + 0.5V$

DC Output Source

or Sink Current (I_O) \pm 50 mA

DC V_{CC} or Ground Current

per Output Pin (I_{CC} or I_{GND}) \pm 50 mA Storage Temperature (T_{STG}) -65° C to +150 $^{\circ}$ C

DC Latch-Up Source

or Sink Current \pm 300 mA

Junction Temperature (T_J)
PDIP

Recommended Operating Conditions

 $\begin{array}{lll} \text{Supply Voltage (V$_{CC}$)} & 4.5 \text{V to } 5.5 \text{V} \\ \text{Input Voltage (V$_{I}$)} & 0 \text{V to V$_{CC}$} \\ \text{Output Voltage (V$_{O}$)} & 0 \text{V to V$_{CC}$} \end{array}$

Operating Temperature (T_A) $-40^{\circ}C$ to $+85^{\circ}C$ Minimum Input Edge Rate $\Delta V/\Delta t$ 125 mV/ns

 $\ensuremath{\text{V}_{\text{IN}}}$ from 0.8V to 2.0V

 $V_{\mbox{\footnotesize CC}}$ @ 4.5V, 5.5V

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. Fairchild does not recommend operation of FACT™ circuits outside databook specifications.

DC Electrical Characteristics for ACTQ

Symbol	Parameter	V _{CC}	T _A = +25°C		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	Units	Conditions	
Symbol		(V)	Тур	Gua	aranteed Limits	Units	Conditions	
V _{IH}	Minimum HIGH Level Input Voltage	4.5	1.5	2.0	2.0	V	V _{OUT} = 0.1V	
		5.5	1.5	2.0	2.0		or V _{CC} – 0.1V	
V _{IL}	Maximum LOW Level	4.5	1.5	0.8	0.8	V	V _{OUT} = 0.1V	
	Input Voltage	5.5	1.5	0.8	0.8		or V _{CC} – 0.1V	
V _{OH}	Minimum HIGH Level	4.5	4.49	4.4	4.4	V	$I_{OUT} = -50 \mu A$	
	Output Voltage	5.5	5.49	5.4	5.4			
							$V_{IN} = V_{IL}or V_{IH}$	
		4.5		3.86	3.76	V	$I_{OH} = -24 \text{ mA}$	
		5.5		4.86	4.76		I _{OH} = -24 mA (Note 2)	
V _{OL}	Maximum LOW Level	4.5	0.001	0.1	0.1	V	I _{OUT} = 50 μA	
	Output Voltage	5.5	0.001	0.1	0.1			
							$V_{IN} = V_{IL}or V_{IH}$	
		4.5		0.36	0.44	V	I _{OL} = 24 mA	
		5.5		0.36	0.44		I _{OL} = 24 mA (Note 2)	
I _{IN}	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	μΑ	$V_I = V_{CC}$, GND	
I _{OZ}	Maximum 3-STATE	5.5		± 0.5	± 5.0	μΑ	$V_I = V_{IL}, V_{IH}$	
	Leakage Current						$V_O = V_{CC}$, GND	
ССТ	Maximum I _{CC} /Input	5.5	0.6		1.5	mA	$V_{I} = V_{CC} - 2.1V$	
OLD	Minimum Dynamic	5.5			75	mA	V _{OLD} = 1.65V Max	
I _{OHD}	Output Current (Note 2)	5.5			-75	mA	V _{OHD} = 3.85V Min	
I _{CC}	Maximum Quiescent Supply Current	5.5		8.0	80.0	μΑ	$V_{IN} = V_{CC}$ or GND	
V _{OLP}	Quiet Output	5.0	1.1	1.5		V	Figure 1, Figure 2	
	Maximum Dynamic V _{OL}						(Note 5)(Note 6)	
V _{OLV}	Quiet Output	5.0	-0.6	-1.2		V	Figure 1, Figure 2	
	Minimum Dynamic V _{OL}						(Note 5)(Note 6)	
V _{IHD}	Minimum HIGH Level Dynamic Input Voltage	5.0	1.9	2.2		V	(Note 5)(Note 7)	
V _{ILD}	Maximum LOW Level Dynamic Input Voltage	5.0	1.2	0.8		V	(Note 5)(Note 7)	

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: PDIP package.

Note 6: Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND.

DC Electrical Characteristics for ACTQ (Continued) Note 7: Max number of data inputs (n) switching. (n – 1) inputs switching 0V to 3V Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f = 1 MHz.

AC Electrical Characteristics

		V _{CC}	$T_A = +25^{\circ}C$ $C_L = 50 \text{ pF}$			$T_A = -40$ °C to +85°C $C_L = 50$ pF		Units
Symbol	Parameter	(V)						
		(Note 8)	Min	Тур	Max	Min	Max	
t _{PLH}	Propagation Delay	5.0	2.0	7.0	9.0	2.0	10.0	ns
t_{PHL}	CP to O _n							
t _{PLH}	Propagation Delay	5.0	2.0	7.0	9.0	2.0	10.0	ns
t _{PHL}	CLR to O _n							
t _{PZH}	Output Enable Time	5.0	2.5	8.0	10.0	2.5	11.0	ns
t_{PZL}	OE to O _n							
t _{PHZ}	Output Disable Time	5.0	1.0	6.0	8.0	1.0	9.0	ns
t_{PLZ}	OE to O _n							
toslh	Output to Output	5.0		0.5	1.0		1.0	ns
toshl	Skew D _n to O _n (Note 9)							

Note 8: Voltage Range 5.0 is 5.0V ± 0.5 V.

Note 9: Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs within the same packaged device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by

AC Operating Requirements

		v _{cc}	T _A = -	+25°C	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	
Symbol	Parameter	(V)	$C_L = 50 \text{ pF}$		C _L = 50 pF	Units
		(Note 10)	Тур	Guar	anteed Minimum	
t _S	Setup Time, HIGH or LOW	5.0	0.5	3.0	3.0	ns
	D to CP					
t _H	Hold Time, HIGH or LOW	5.0	0	1.5	1.5	ns
	D _n to CP					
t _S	Setup Time, HIGH or LOW	5.0	0	3.0	3.0	ns
	EN to CP					
t _H	Hold Time, HIGH or LOW	5.0	0	1.5	1.5	ns
	EN to CP					
t _W	CP Pulse Width	5.0	2.5	4.0	4.0	ns
	HIGH or LOW					
t _W	CLR Pulse Width, LOW	5.0	3.0	4.0		ns
t _{rec}	CLR to CP	5.0	1.5	3.5	4.0	ns
	Recovery Time					

Note 10: Voltage Range 5.0 is 5.0V ±0.5V

Capacitance

Symbol	Symbol Parameter		Units	Conditions
C _{IN} Input Capacitance		4.5	pF	V _{CC} = OPEN
C _{PD} Power Dissipation Capacitance		54	pF	V _{CC} = 5.0V

FACT Noise Characteristics

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

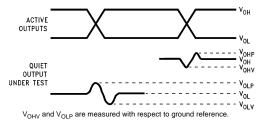
Equipment:

Hewlett Packard Model 8180A Word Generator PC-163A Test Fixture

Tektronics Model 7854 Oscilloscope

Procedure:

- 1. Verify Test Fixture Loading: Standard Load 50 pF, 500Ω .
- 2. Deskew the HFS generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
- 3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
- Set the HFS generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and effect the results of the measurement



Input pulses have the following characteristics: f = 1 MHz, $t_r = 3 \text{ ns}$, t_f = 3 ns, skew < 150 ps

FIGURE 1. Quiet Output Noise Voltage Waveforms

Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.

V_{OLP}/V_{OLV} and V_{OHP}/V _{OHV}:

- · Determine the guiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure $V_{\mbox{\scriptsize OLP}}$ and $V_{\mbox{\scriptsize OLV}}$ on the quiet output during the worst case transition for active and enable. Measure $V_{\mbox{\scriptsize OHP}}$ and $V_{\mbox{\scriptsize OHV}}$ on the quiet output during the worst case transition for active and enable.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

VILD and VIHD:

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL} , until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed VIH limits. The input LOW voltage level at which oscillation occurs is defined as V_{ILD}.
- Next decrease the input HIGH voltage level, V_{IH} , until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V $_{\rm IL}$ limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V IHD.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

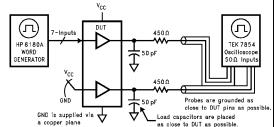
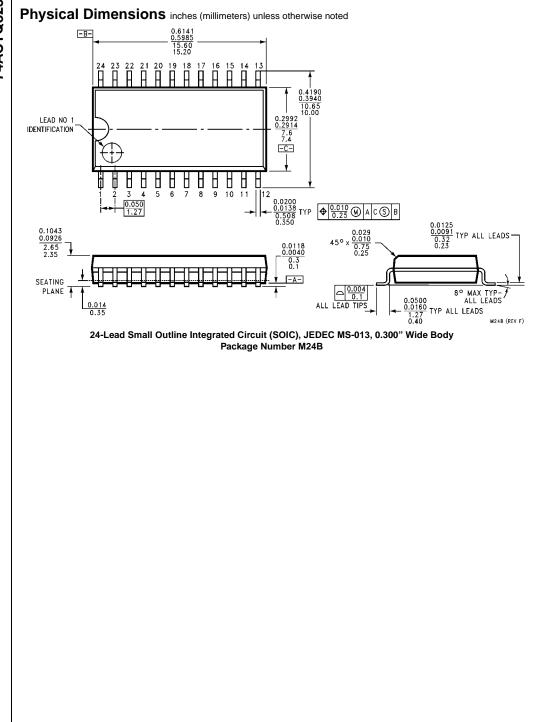
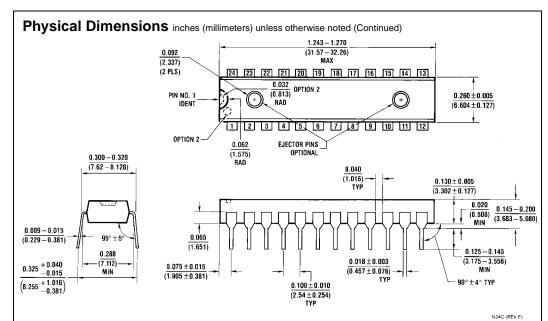


FIGURE 2. Simultaneous Switching Test Circuit





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300" Wide Package Number N24C

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

www.fairchildsemi.com